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# Multistate Resistance Stability for 5 Bit, 32 State Ferroelectric (Hf,Zr)O<sub>2</sub> Tunnel Junctions

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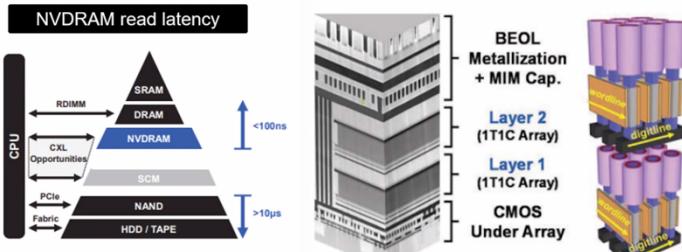
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# Ferroelectrics

- Introduction into select ferroelectric devices
  - Ferroelectric  $(\text{Hf},\text{Zr})\text{O}_2$  - a quick refresher in applications
  - FTJ work continued from WINDS 2023
- TaN and Ta based electrodes
  - Basis of an individual FTJ device, area scaling
  - Conduction mechanisms – NbN/Nb electrodes (WINDS 2022)
- Multi (2) resistance state FTJ devices
  - Multistate resistance using write voltage and read voltage stability
  - Pyroelectric measurements for why it isn't stable
- Multi State (32) resistance with read stability

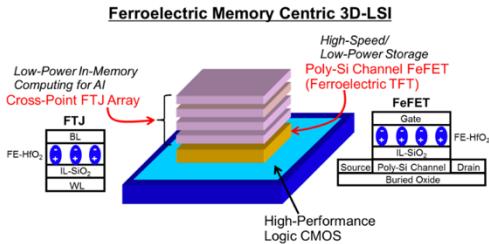
# What's a useful app for a ferroelectric?

## FeRAM – Micron's 32Gb NVDRAM



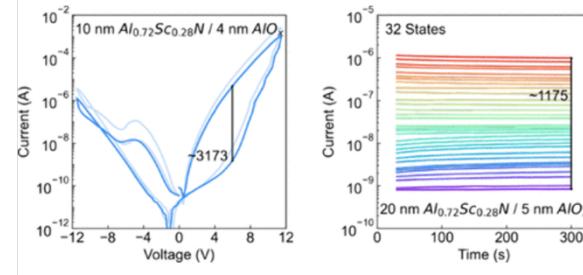
Ramaswamy, N., et al. "NVDRAM: A 32Gb dual layer 3D stacked non-volatile ferroelectric memory with near-DRAM performance for demanding AI workloads." 2023 International Electron Devices Meeting (IEDM). IEEE, 2023.

## Toshiba Memory efforts with Sony



M. Saitoh et al., "HfO<sub>2</sub>-based FeFET and FTJ for Ferroelectric-Memory Centric 3D LSI towards Low-Power and High-Density Storage and AI Applications," 2020 IEEE International Electron Devices Meeting (IEDM), San Francisco, CA, USA, 2020, pp. 18.1.1-18.

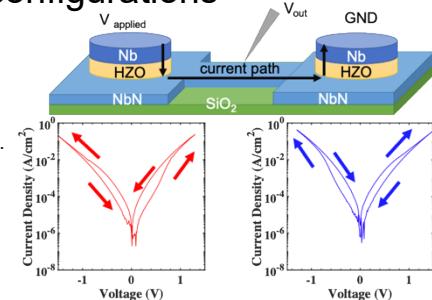
## Emerging high temperature AlScN devices



Kim, K. H., Han, Z., Zhang, Y., Musavigharavi, P., Zheng, J., Pradhan, D. K., ... & Jariwala, D. (2024). Multistate, Ultrathin, Back-End-of-Line-Compatible AlScN Ferroelectric Diodes. *ACS nano*.

## Unique logic configurations

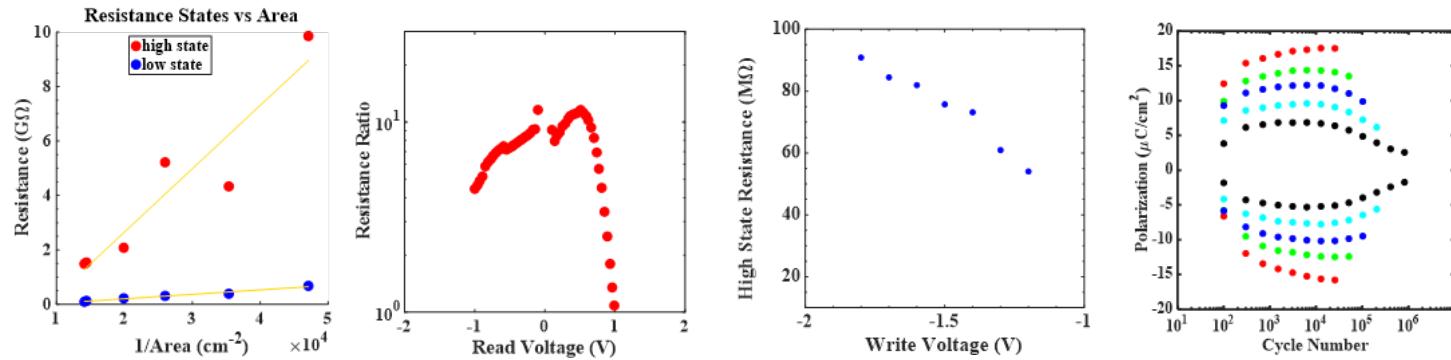
Haglund-Peterson, J., Aronson, B. L., Jaszewski, S. T., Habermehl, S., Esteves, G., Conley, J. F., ... & Henry, M. D. (2024). Nonvolatile memory cells from hafnium zirconium oxide ferroelectric tunnel junctions using Nb and NbN electrodes. *Journal of Applied Physics*, 135(9).



# Last year at WINDS

- Progress in TaN/Ta based FTJ for insertion into a BEOL, MIM Cap module process.
- Control over resistance is complex but interesting for a circuit designer, via:

- Area scalable
- Read Voltage
- Write Voltage

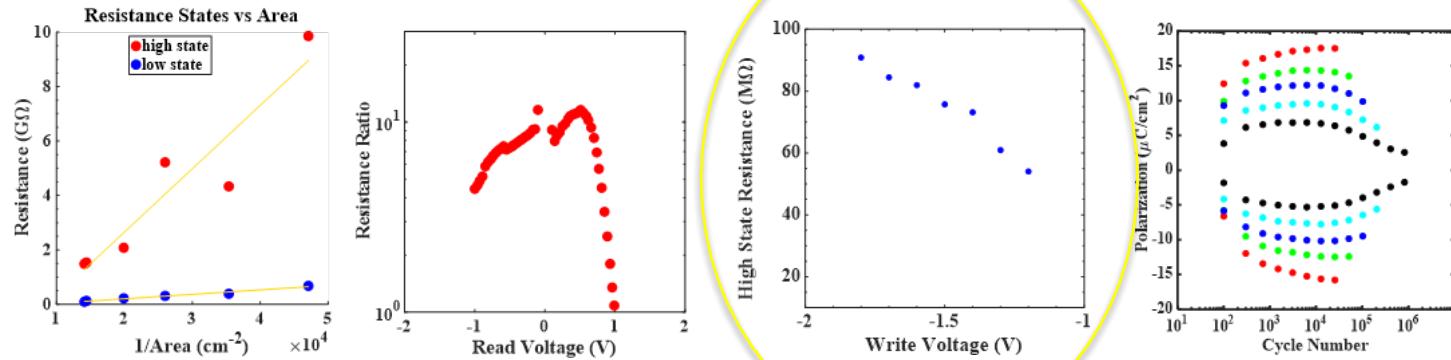


- With a whole lot of in between states needing repeatability.

# Last year at WINDS

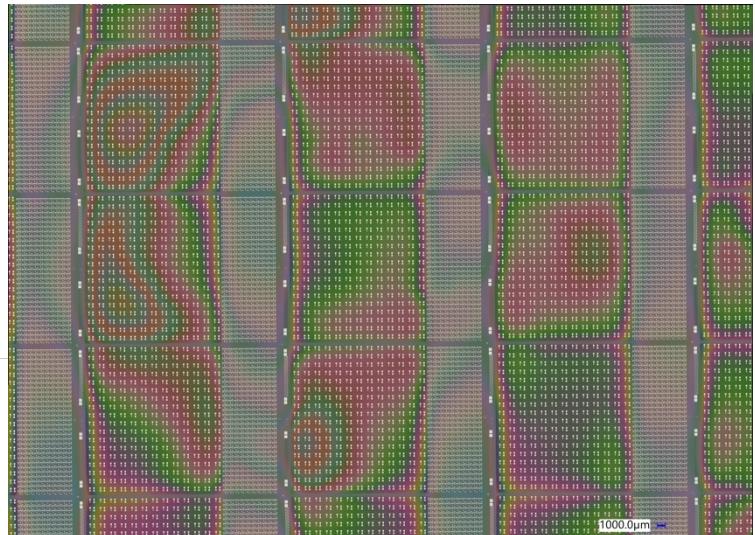
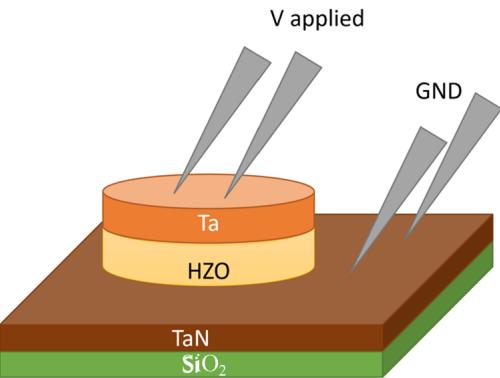
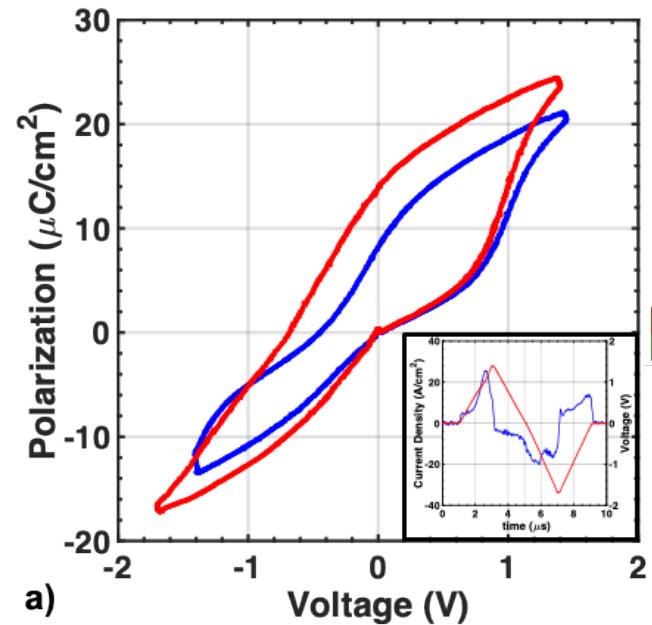
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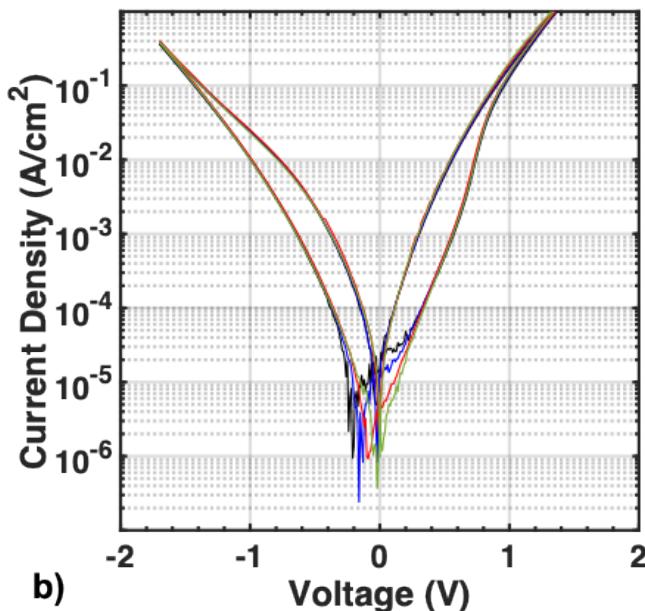
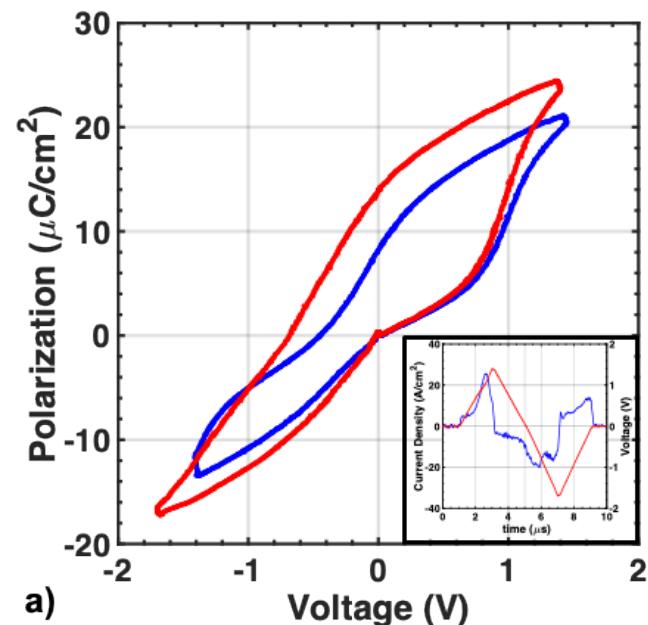
- With a whole lot of in between states **needing repeatability**.

# Back to basics - how do we build this



Devices were fabricated using a planarized 3 metal layer, 150 mm process. Bottom layer is  $\text{TaN}$  with a 6 nm  $\text{HZO}$  and  $\text{Ta}$  top electrode. The wafer is planarized with CVD oxide and vias etched to connect to a top electrode (Ti/Al).

# Back to basics - how does this perform



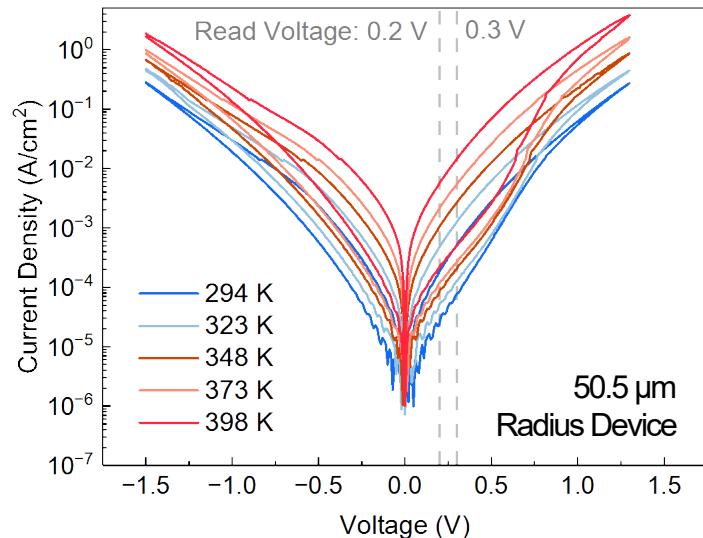
Area normalized 20, 30, 40, and 50  $\mu\text{m}$  radius devices.

With a voltage range of -1.7 V to 1.4 V, and noting the imprint in the PE loop, we observe a repeatable FTJ with 10x change in resistance.

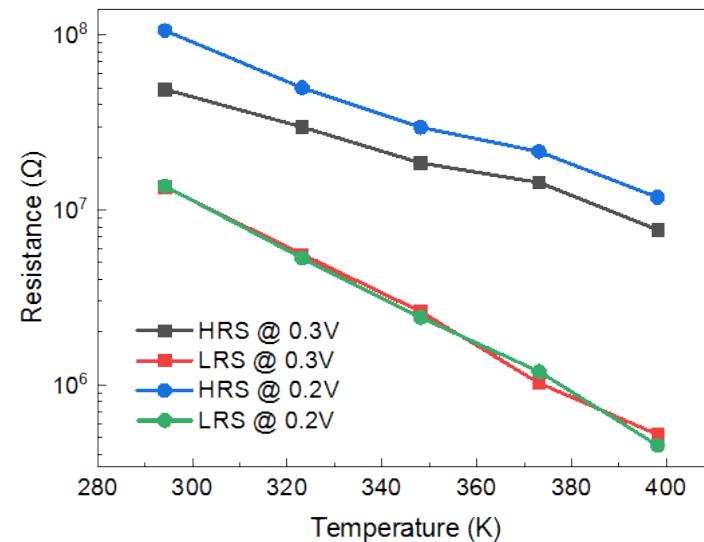
# Temp Dependence of Current – Fitting the Conduction (Nb & NbN electrodes)

- Temperature used to derive current transport mechanisms
- Devices cycled 5 times at  $\sim 1\text{Hz}$  for wakeup
- Chuck temperature varied from  $21\text{ }^{\circ}\text{C}$  (294 K) to  $125\text{ }^{\circ}\text{C}$  (398 K)

LRS demonstrates **higher** temperature dependence than HRS

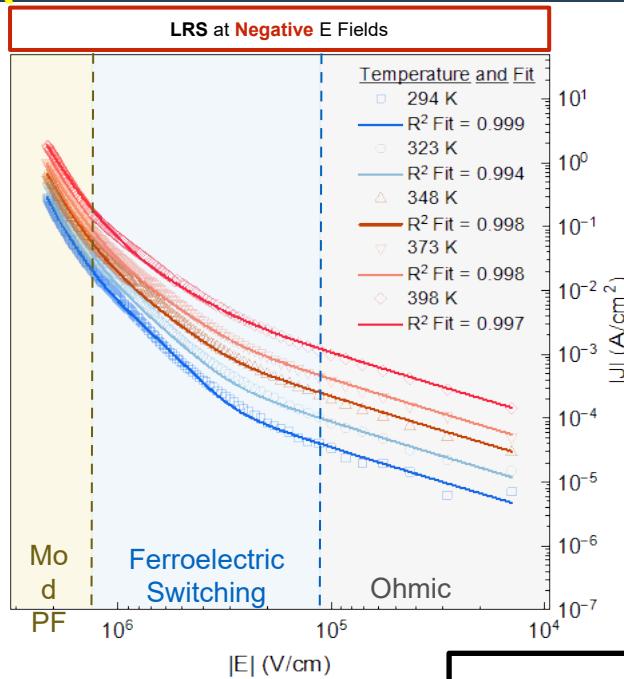


Current Density vs. Voltage Curves

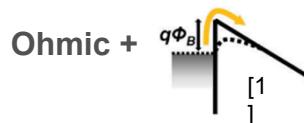


High Resistance State (HRS) & Low Resistance State (LRS) Across Temperature

# Low Resistance State Current Transport (Nb & NbN electrodes)

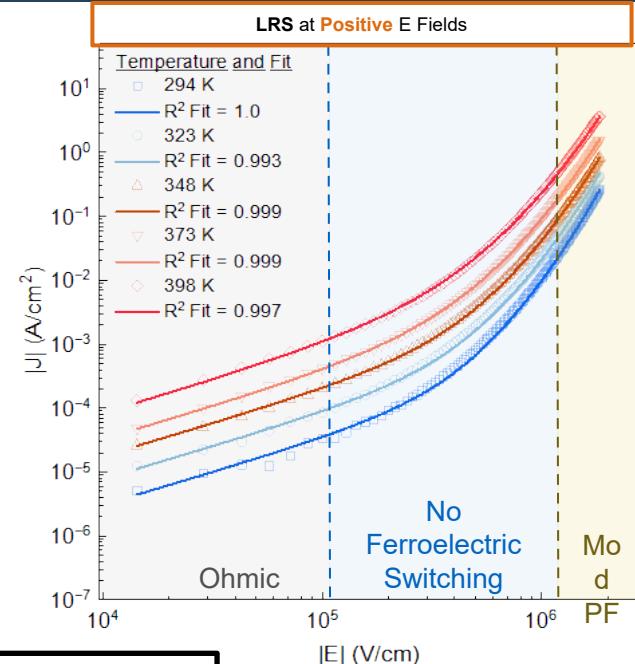
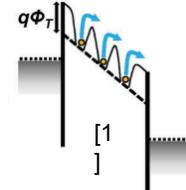


Current Transport =



Ferroelectric  
Switching from  
Domain Nucleation +

Modified Poole-  
Frenkel Conduction



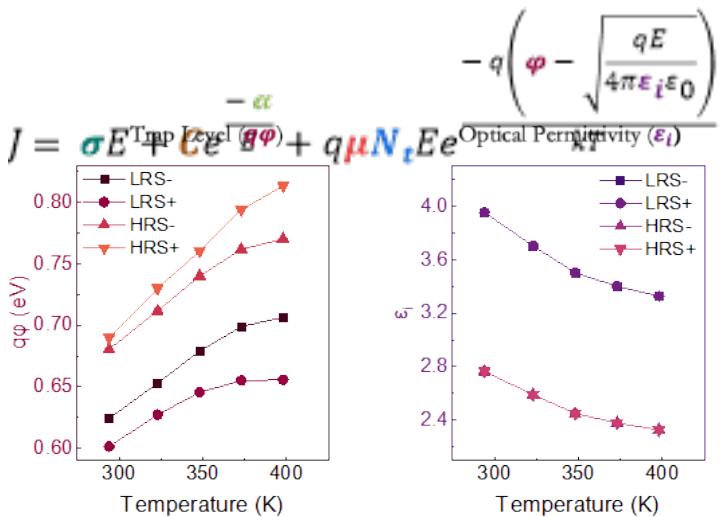
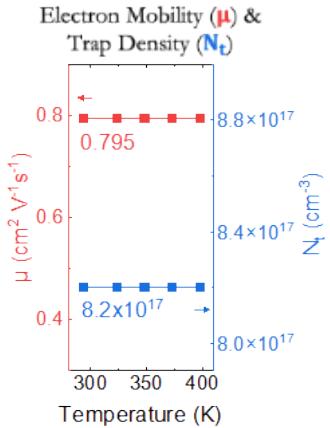
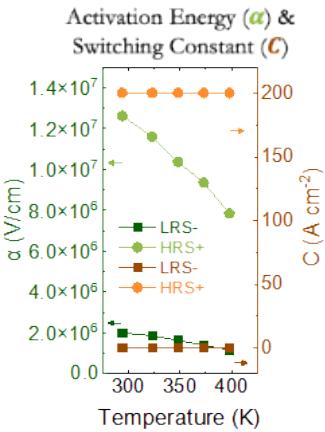
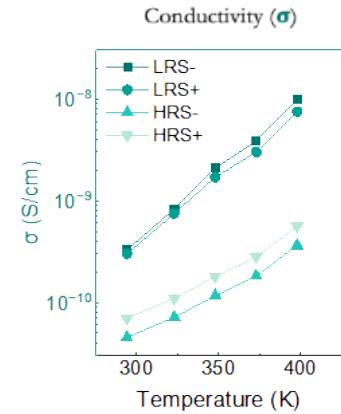
[1] Hwang, J., et al. (2024). Small 20(9): e2305271.

$I = \sigma E$     $Ce = \epsilon$     $q\mu N_i Ee = kT$

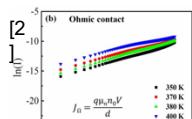
$$-\alpha$$

$$-q \left( \varphi - \sqrt{\frac{qE}{4\pi\epsilon_i\epsilon_0}} \right)$$

# Fitted Constants for Current Transport Equation (Nb & NbN electrodes)



Matches literature magnitude  $\sigma \approx 3 \times 10^{-9}$  S/cm [1] & trend with temperature [2]



[1] Reddy, P. R. S. (2024). Materials Technology Reports 2 (1).

[2] Zhang, Y., et al. (2020). ACS Appl Mater Interfaces 12

Ferro. Domain Nucleation [3]:  
 $i_{switch} = C \frac{dn}{dt} = Ce^{-\frac{\alpha(T)}{k}}$

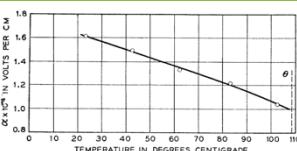
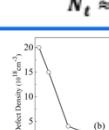


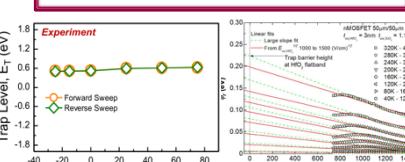
FIG. 16. Activation energy  $\alpha$  versus temperature.

Constant for all resistance states.  
 Matches literature:  $\mu \approx 0.43 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  [4],  
 $N_t \approx 1 \times 10^{18}$  [5]



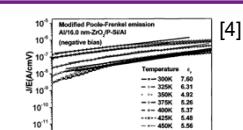
[4] Wang, M.-T., et al. (2005). Journal of The Electrochemical Society 152 (3).  
 [5] Pal, A., et al. (2017). Applied Physics Letters 110 (12).

Matches literature:  $\varphi_t \approx 0.6 \text{ eV}$  [6] and trend with temperature [7].



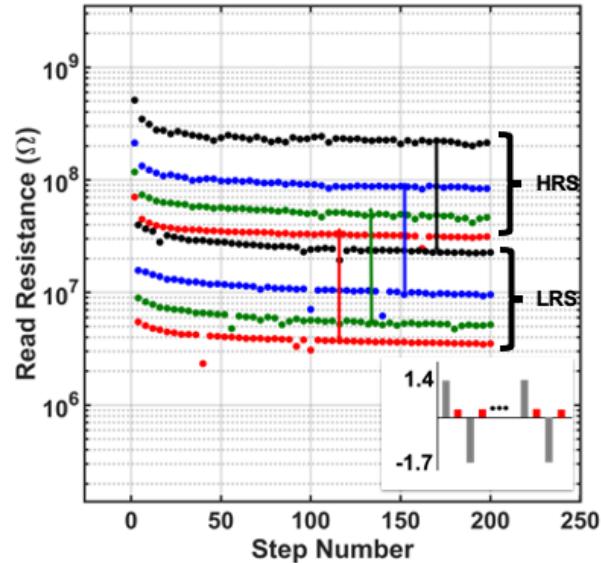
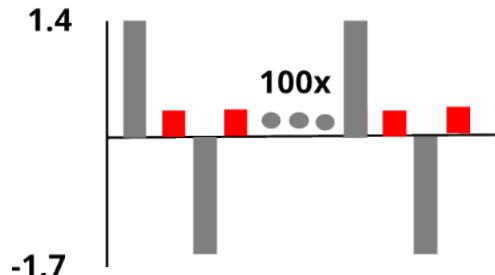
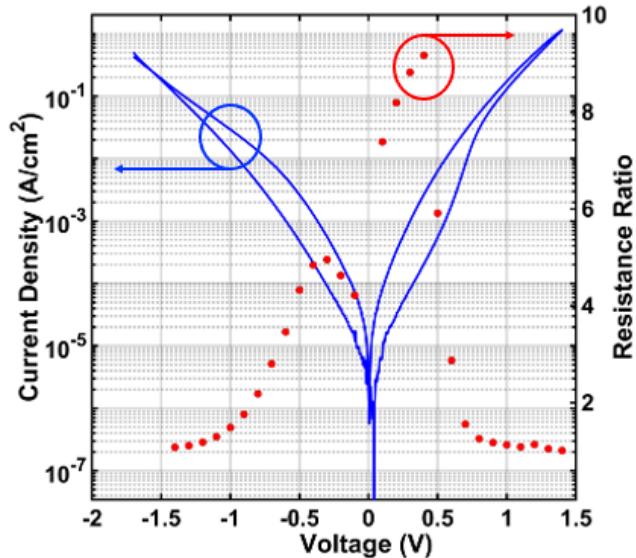
[6] Mallick, A., et al. (2023). Applied Physics Letters 112 (12).  
 [7] Southwick, R. G., et al. (2010). Transactions on

Matches literature:  $\epsilon_t \approx 4.5$  [8], and trend with temperature [4].



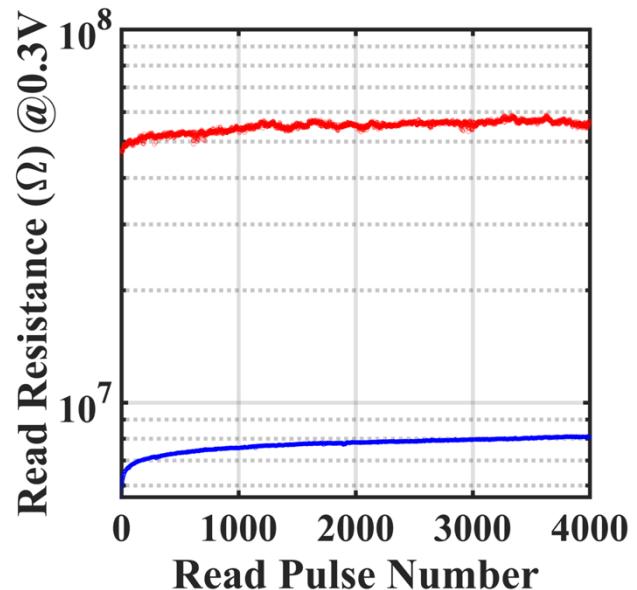
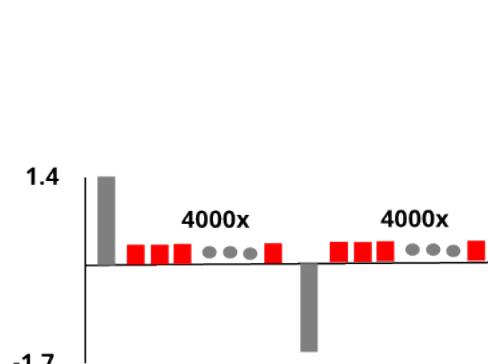
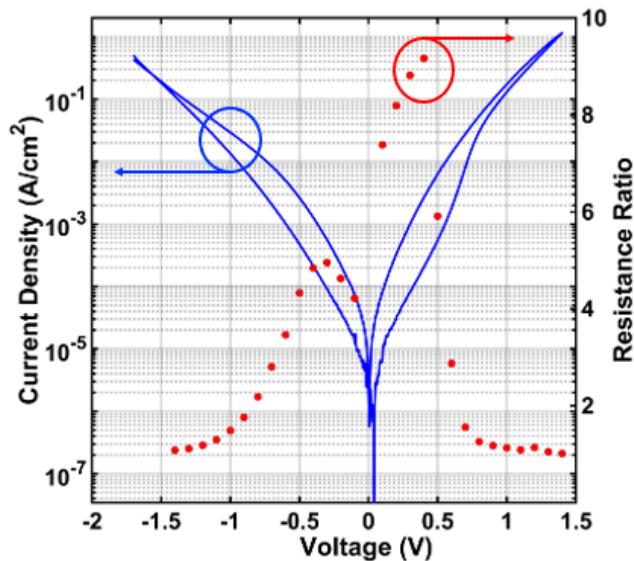
ZrO

# FTJ flips conduction from polarization – 2 state



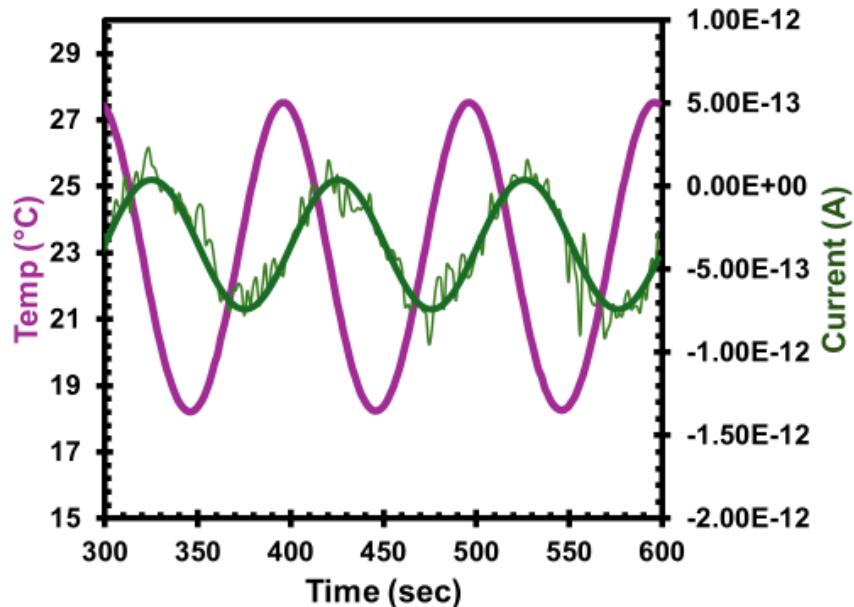
As the polarization switches, the HZO undergoes wake up; a process in which cycling the film moves oxygen vacancies. This stabilizes the orthorhombic phase and increases the  $P_r$  – for the FTJ it means increasing the current density.

# FTJ flips conduction from polarization – 2 state

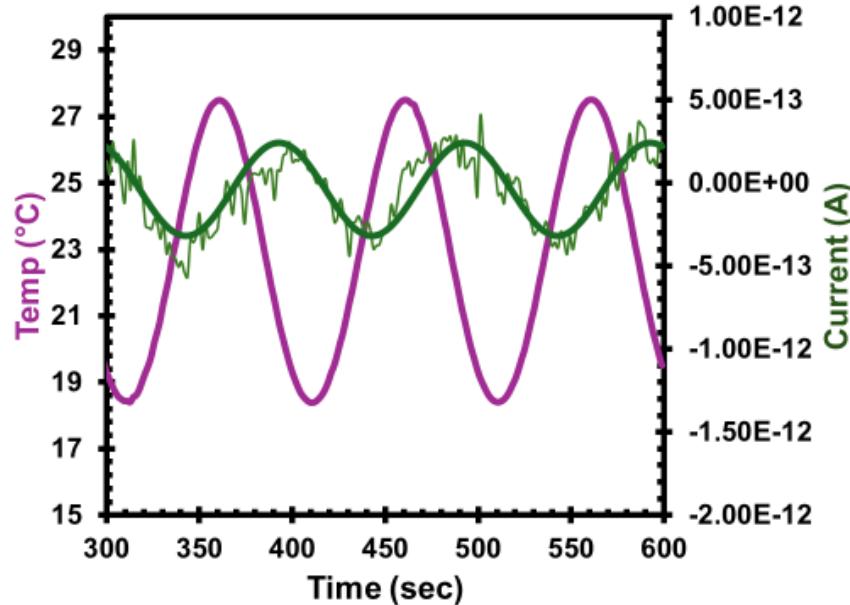


But what happens if you write a state and want to read it out ... a lot. Turns out, the act of reading depolarizes the HZO and how much depends on direction of polarization.

# Pyroelectric Measurements with -1.5 V pole, -1.5 V write, with 50 x, +0.3V reads



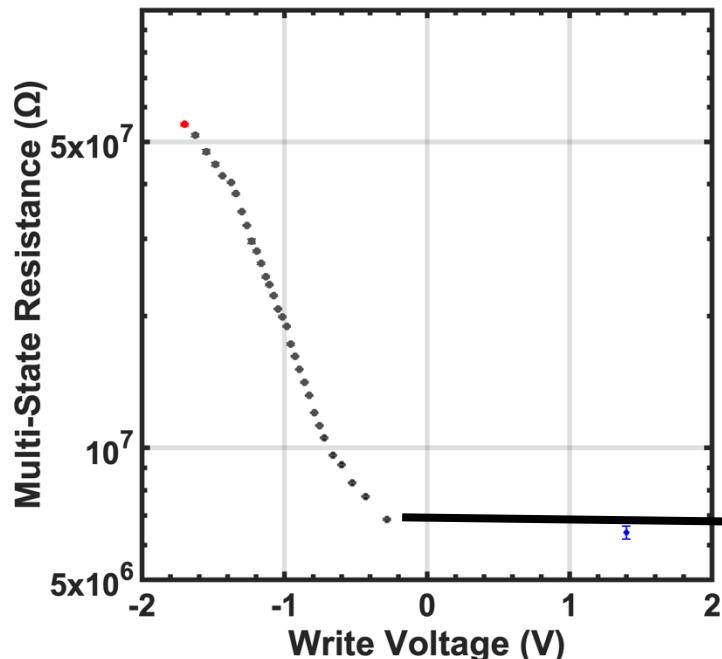
Pyroelectric coefficient:  $-23.14 \mu\text{C m}^{-2} \text{K}^{-1}$



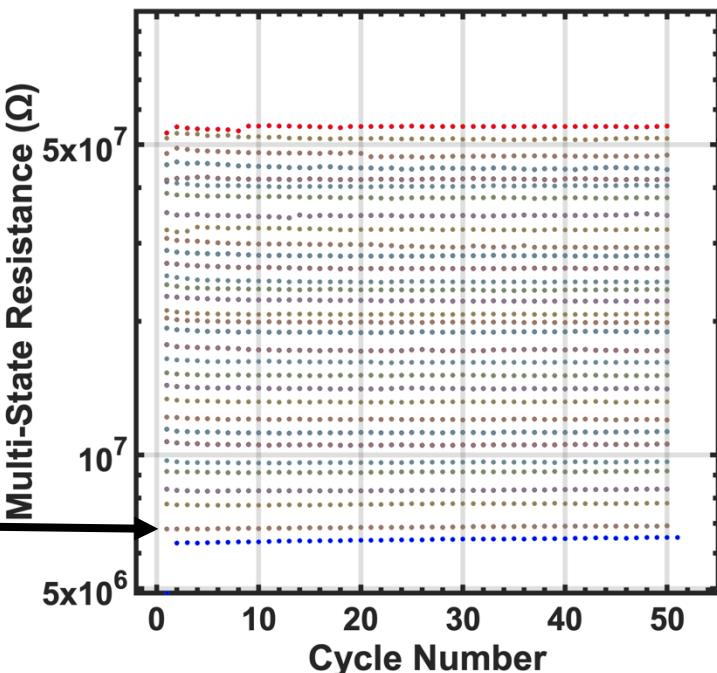
Pyroelectric coefficient:  $-15.83 \mu\text{C m}^{-2} \text{K}^{-1}$

Decrease in magnitude of pyroelectric coefficient consistent with domain depoling.

# Multistate Resistance - 32 States

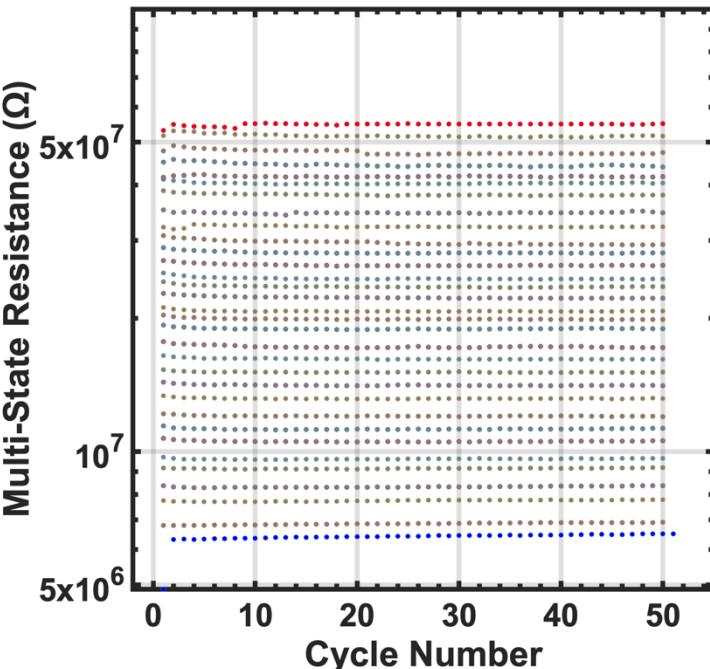
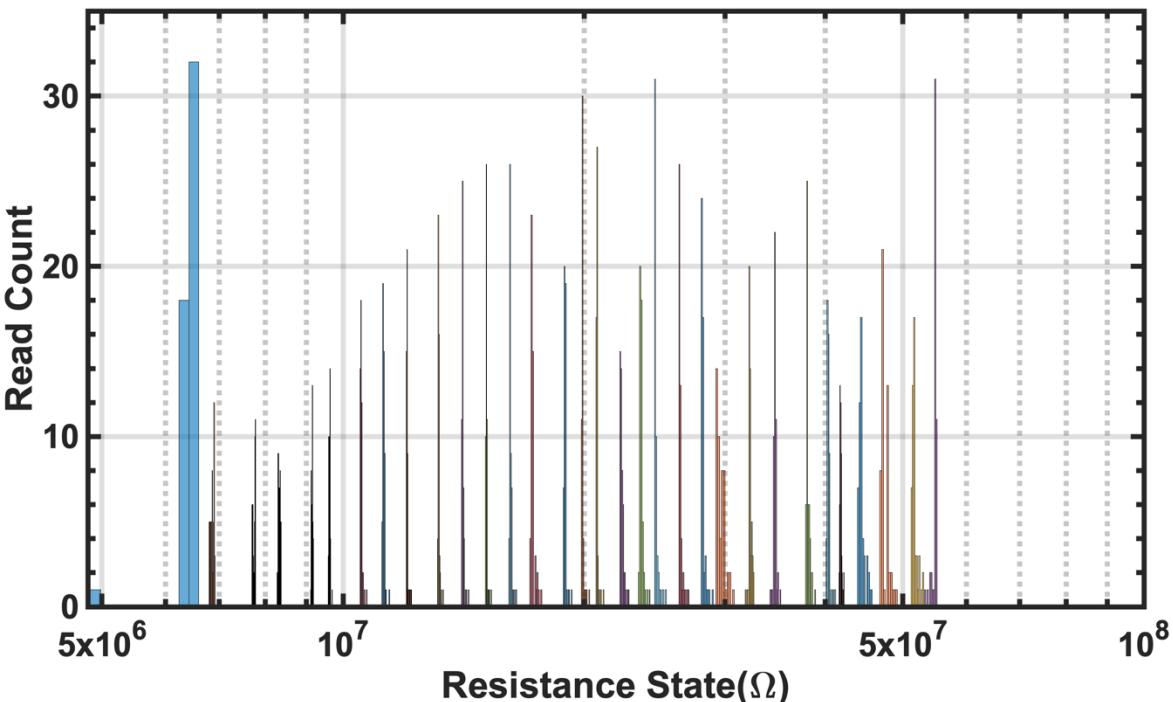


Each memory state is set by a write voltage partially depolarizing the HZO to set the intermediate resistance state between the LRS and HRS.



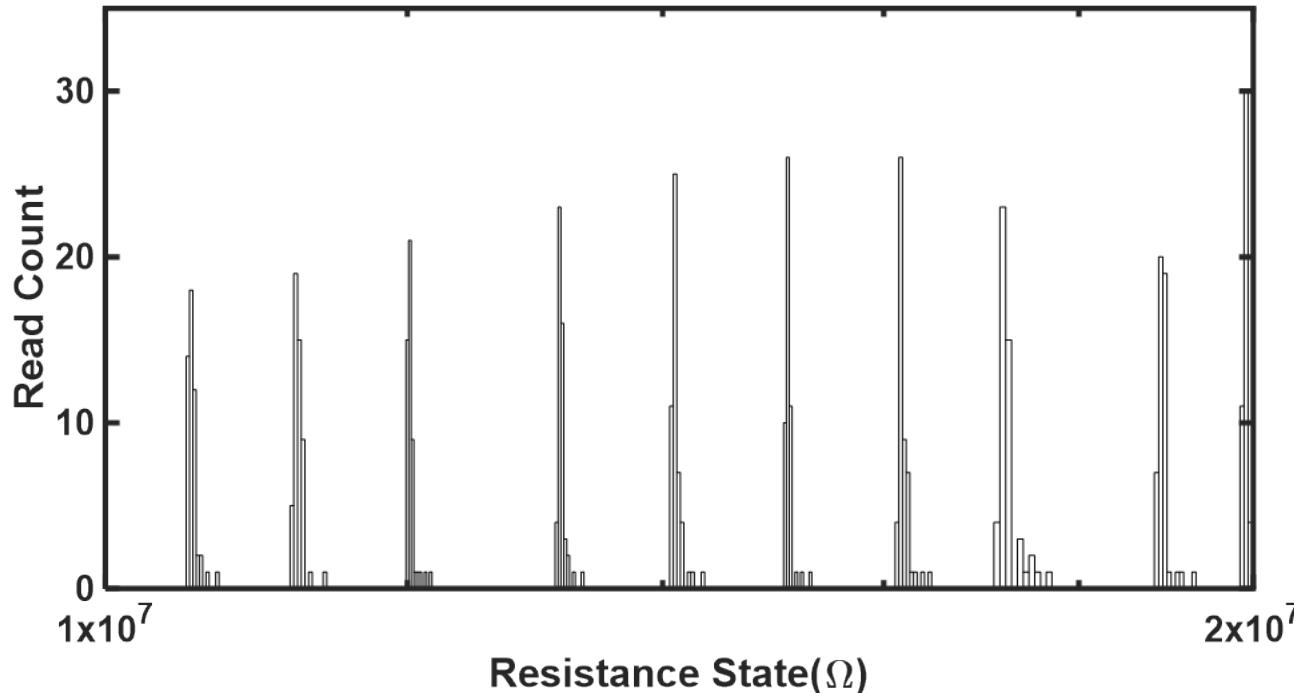
Here we separated the writes from 0 to -1.7 V (wrote 2x) and then read each state 50 times. There is some curvature in the stability of the reads and that is due to the read pulse depolarizing the HZO.

# Multistate Resistance - 32 States



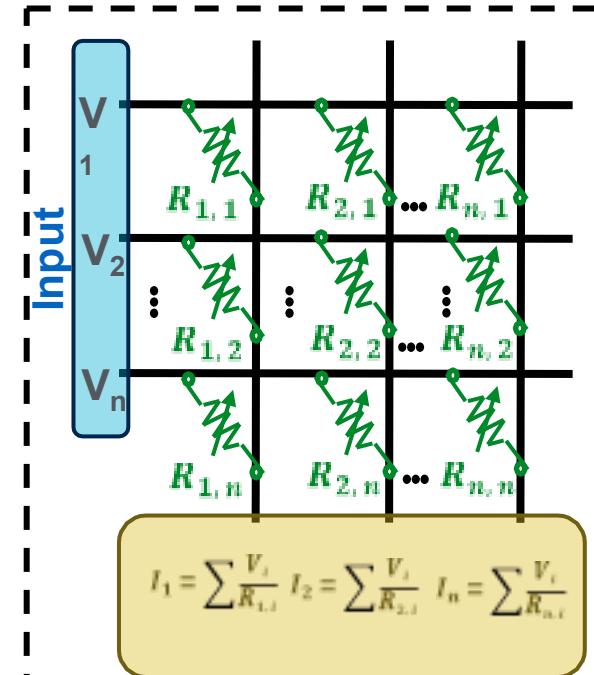
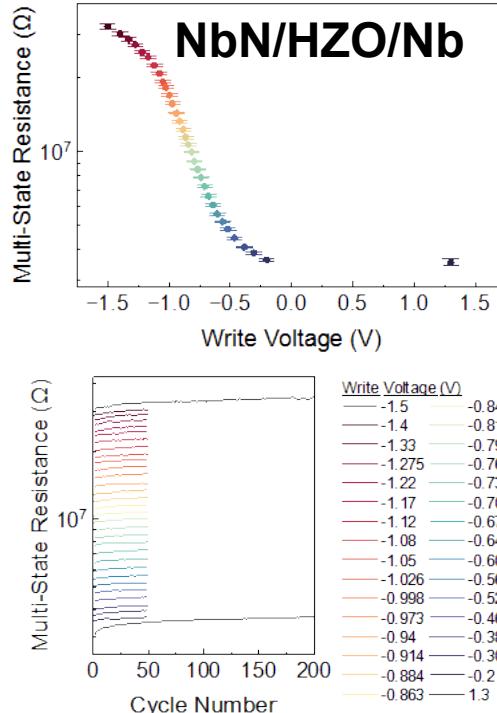
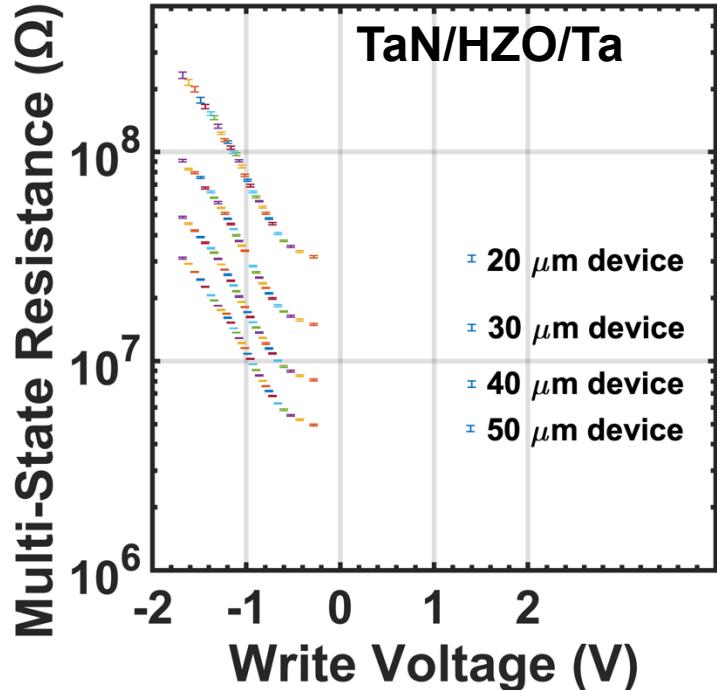
To get an idea of the movement and guarantee of separation, the read resistances were binned into 10 bins. The negative write state starts in a high resistance and settles lower.

# Multistate Resistance - 32 States



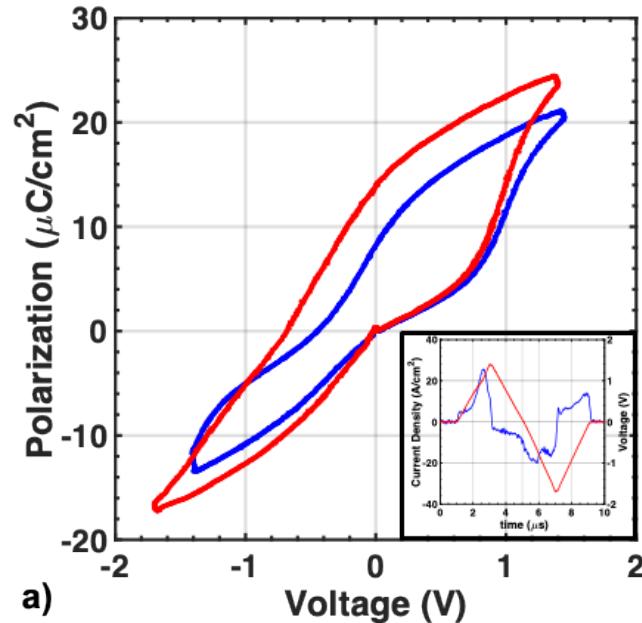
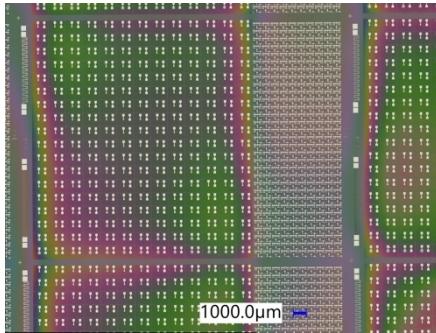
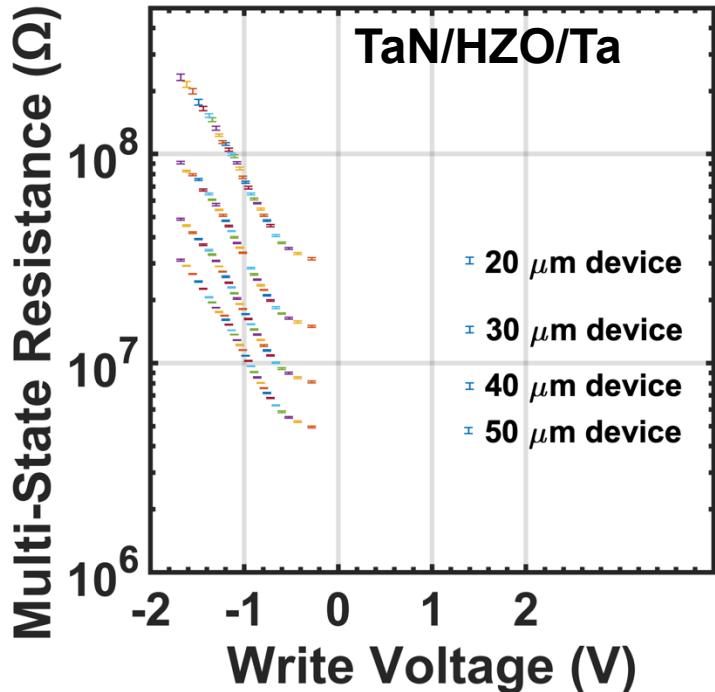
Zooming in on the  $1-2 \times 10^7 \Omega$ . We note that the resistance starts high and drops low.

# Multistate Resistance - 32 States – Area Scaling



It is interesting that we can now make a matrix where each column can be area scaled and resistance set in one of 32 resistance states...

# Mahalo! A hui hou!



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